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Bib Data Sheet

CONFIRMATION NO. 2738

SERIAL NUMBER 10/670,387	FILING DATE 09/26/2003 RULE	CLASS 382	GROUP ART UNIT 2625	ATTORNEY DOCKET NO. 02887.0251
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APPLICANTS

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** CONTINUING DATA *gp* *****

** FOREIGN APPLICATIONS *gp* *****
 JAPAN 2002-281572 09/26/2002

IF REQUIRED, FOREIGN FILING LICENSE GRANTED
 ** 01/03/2004

Foreign Priority claimed 35 USC 119 (a-d) conditions met Verified and Acknowledged	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance Examiner's Signature <i>osd</i> Initials	STATE OR COUNTRY JAPAN	SHEETS DRAWING 14	TOTAL CLAIMS 30	INDEPENDENT CLAIMS 12
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TITLE
 Pattern measurement method, manufacturing method of semiconductor device, pattern measurement apparatus, and program

FILING FEE RECEIVED 1816	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:	<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue)
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